Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/554,263	KIM, SUKYOON
Examiner	Art Unit

3679

David E. Bochna

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated the previous search	7/2/2007	DB
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